Notice of References Cited					Reexamin		Applicant(s)/Patent Under Reexamination KIM ET AL.	
				Examiner			nit _	
				Julian Mer			Page 1 of 1	
				U.S. PATENT DOCU	MENTS			
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY		Name		Classification	
	Α	US-						
	В	US-						
	С	US-						
	D	US-						
	Е	US-						
	F	US-						
-	G	US						
	H/	US-						
	/	US-						
	J	US-						
	К	US-						
	L	US-						
	М	US-						
				FOREIGN PATENT DO	CUMENTS			
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Country Name		Classification	
	N/	1-265454	10-1989	Japan	Kita et al.		H01M 4/50	
	7							
	0			l				
-	O P							
	-							
	Р							
	P Q							
	P Q R							
	P Q R S			NON-PATENT DOC				
*	P Q R S	Inclu	de as applicable	NON-PATENT DOC e: Author, Title Date, Pu		ume, Pertinent Pages)		
*	P Q R S	Inclu	de as applicable			ume, Pertinent Pages)		
*/	P Q R S T	Inclu	de as applicable			ume, Pertinent Pages)		
*	P Q R S T	Inclu	de as applicable			ume, Pertinent Pages)		
*	P Q R S T U	Inclu	de as applicable			ime, Pertinent Pages)		
*	P Q R S T U	Inclu	de as applicable			ume, Pertinent Pages)		
*	P Q R S T U V	Inclu	de as applicable			ime, Pertinent Pages)		
*/	P Q R S T U V V W	is reference is not being furnished with I-YYYY format are publication dates. Cla		e: Author, Title Date, Pu		Ime, Pertinent Pages)		